

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1038	703/14.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2006/08/06 17:02
L2	78	703/14.ccls. and @pd>"20060401"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2006/08/06 17:08
L3	8	09/724,585	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2006/08/06 17:43
L4	1953	instrumentation and statistic\$1 and @ad<"20010901"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2006/08/06 17:44
L5	665	L4 and (logic or hdl or verilog or vhdl)	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2006/08/06 17:45
L6	300	L5 and (simulat\$4 or emulat\$4)	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2006/08/06 17:45

Scholar

Results 1 - 10 of about 6,700 for **instrumentation logic simulation**. (0.15 seconds)

**Fault modeling and logic simulation of CMOS and MOS integrated circuits - group of 2 »**

[All articles](#) [Recent articles](#)

RL Wadsack - Bell System Technical Journal, 1978 - adsabs.harvard.edu

Title: Fault modeling and **logic simulation** of CMOS and MOS integrated circuits Authors:

Wadsack, R. L. Journal: Bell System Technical Journal, vol. ...

Cited by 231 - [Web Search](#)

**HITEC: a test generation package for sequential circuits - group of 2 »**

T Niermann, JH Patel, STS Inc, CA Los Altos - Design Automation. EDAC. Proceedings of the European ..., 1991 - [ieeexplore.ieee.org](#)

... circuits, Iyengar, V.; Chakrabarty, K.; Murray, BT **Instrumentation** and Measurement ...

48, Efficient sequential test generation based on **logic simulation**, Shuo Sheng ...

Cited by 433 - [Web Search](#)

**Dynamic test emulation for EDA-based mixed-signal test development automation - group of 2 »**

JQ Xia, T Austin, N Khouzam, CDS Inc, CA San Jose - Test Conference, 1995. Proceedings., International, 1995 - [ieeexplore.ieee.org](#)

... Modeling of the ATE **instrument**, the DUT and the ... on a solution [8]. A mixed-signal

**simulation** backplane simulates ... switch-level, gate-level **logic**, and behavioral ...

Cited by 11 - [Web Search](#) - [BL Direct](#)

**Testing conventional logic and memory clusters using boundary scan devices as virtual ATE channels**

P Hansen, T Inc, MA Boston - Test Conference, 1989. Proceedings. Meeting the Tests of ..., 1989 - [ieeexplore.ieee.org](#)

... and while a few commercial devices such as Texas **Instruments'** SCOPETM OCTAL ... which

are applied against the cluster model in **logic** and fault **simulation**. ...

Cited by 17 - [Web Search](#)

**Virtual Test of Noise and Jitter Parameters - group of 4 »**

K Helmreich, G Reinhardt - Proc. International Test Conference, 1996 - [doi.ieeecomputersociety.org](#)

... and tester components even for virtual **logic** test. ... tester modelling to modelling

the various **instruments** as individual ... and to rely on the **simulation** clock to ...

Cited by 7 - [Web Search](#) - [BL Direct](#)

**The NAPA adaptive processing architecture - group of 6 »**

CR Rupp, M Landguth, T Garverick, E Gomersall, H ... - FPGAs for Custom Computing Machines, 1998. Proceedings. IEEE ..., 1998 - [ieeexplore.ieee.org](#)

... with inadequate debugging and **instrumentation** support ... typically initiate direct

configurable **logic** pipeline action ... development, run time support, and **simulation**. ...

Cited by 105 - [Web Search](#)

**Unifying simulation and execution in a design environment for FPGA systems - group of 4 »**

BL Hutchings, BE Nelson - Very Large Scale Integration (VLSI) Systems, IEEE ..., 2001 - [ieeexplore.ieee.org](#)

... To illustrate the use of **instrumentation** code in both **simulation** and execution a

complete but ... public class traffic extends **Logic** implements Observable f ...

Cited by 8 - [Web Search](#) - [BL Direct](#)

**Mcm Test Vectors from Logic Simulation**

A Flint - Proc. SPIE, 1996 - adsabs.harvard.edu

Title: Mcm Test Vectors from **Logic Simulation** Authors: Flint, Andrew Journal:

Proc. SPIE Vol. 2794, Proceedings of the 1996 International ...

Cited by 3 - [Web Search](#) - [BL Direct](#)

**Functional design verification by multi-level simulation - group of 2 »**

K Tham, R Willoner, D Wimp - Proceedings of the 21st conference on Design automation, 1984 - [portal.acm.org](#)

... A **simulator**, #SIM, acts as an **instrumentation** shell around the MAINSAIL model allowing ...

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Results for "((instrumentation<and>logic)<and>simulation) <and> (pyr >= 1951 <and> pyr..."

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IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

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- ☐ **1. Subject Index [1951-1971]**  
[Aerospace and Electronic Systems, IEEE Transactions on](#)  
 Volume 36, Issue 3, Part 2, July 2000 Page(s):45 - 121  
 Digital Object Identifier 10.1109/TAES.2000.869526  
[AbstractPlus](#) | Full Text: [PDF\(10988 KB\)](#) IEEE JNL  
[Rights and Permissions](#)
- ☐ **2. 1972-1999 combined index IEEE transactions on aerospace and electronic systems vols. aes-8-35 [Subject Index]**  
[Aerospace and Electronic Systems, IEEE Transactions on](#)  
 Volume 36, Issue 3, Part 2, July 2000 Page(s):68 - 262  
 Digital Object Identifier 10.1109/TAES.2000.869528  
[AbstractPlus](#) | Full Text: [PDF\(23324 KB\)](#) IEEE JNL  
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- ☐ **3. IEEE transactions on magnetics cumulative index 1985-2000 volumes 21-36 [Subject Index]**  
[Magnetics, IEEE Transactions on](#)  
 Volume 37, Issue 6, Part 2, Nov 2001 Page(s):467 - 1288  
 Digital Object Identifier 10.1109/TMAG.2001.966142  
[AbstractPlus](#) | Full Text: [PDF\(7236 KB\)](#) IEEE JNL  
[Rights and Permissions](#)
- ☐ **4. Fault tolerance in systems design in VLSI using data compression under constraints of failure probabilities**  
 Das, S.R.; Ramamoorthy, C.V.; Assaf, M.H.; Petriu, E.M.; Wen-Ben Jone;  
[Instrumentation and Measurement, IEEE Transactions on](#)  
 Volume 50, Issue 6, Dec. 2001 Page(s):1725 - 1747  
 Digital Object Identifier 10.1109/19.982974  
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(495 KB\)](#) IEEE JNL  
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- ☐ **5. 1986-1999 combined index IEEE aerospace and electronic systems magazine vols. 1-14 [Subject Index]**  
[Aerospace and Electronic Systems, IEEE Transactions on](#)  
 Volume 36, Issue 3, Part 2, July 2000 Page(s):21 - 85  
 Digital Object Identifier 10.1109/TAES.2000.869530  
[AbstractPlus](#) | Full Text: [PDF\(7220 KB\)](#) IEEE JNL  
[Rights and Permissions](#)
- ☐ **6. Subject Index**  
[Applied Superconductivity, IEEE Transactions on](#)  
 Volume 11, Issue 4, Dec. 2001 Page(s):4200 - 4303

Scholar

Results 1 - 10 of about 184 for **tri-state bus statistics**. (0.06 seconds)

**Tri-state bus conflict checking method for ATPG using BDD - group of 3 »**

[All articles](#) [Recent articles](#)

Y Koseko, T Ogiwara, S Murai - Proceedings of the 1993 IEEE/ACM international conference on ... , 1993 - portal.acm.org

... Table 1 **Statistics** of busses and selectors #of Outputs of ... are detected that violate the **bus** design rule ... enabling/disabling logic to the **tri-state** drivers for ...

[Cited by 3](#) - [Web Search](#) - [BL Direct](#)

**Low-power encodings for global communication in CMOS VLSI - group of 6 »**

MR Stan, WP Burleson - Very Large Scale Integration (VLSI) Systems, IEEE ... , 1997 - ieeexplore.ieee.org

... for Low Power Until now we have only considered **tri-state** buses on ... decrease in average power dissipation depends on the **statistics** of the **bus** transfers and ...

[Cited by 83](#) - [Web Search](#) - [BL Direct](#)

**DEFUSE: a deterministic functional self-test methodology for processors - group of 11 »**

L Chen, S Dey - VLSI Test Symposium, 2000. Proceedings. 18th IEEE, 2000 - ieeexplore.ieee.org

... As Table 2. **Statistics** on the self-test programs ... d1 d2 s1 s2 **bus** d1 d2 s1 s2 **bus** **tri-state** buffer selector Figure 10. Converting **tri-state** buffers to selectors ...

[Cited by 40](#) - [Web Search](#)

**A hybrid prototyping platform for dynamically reconfigurable designs - group of 3 »**

T Rissa, J Niittylahti - Proc. 10th Int. Workshop on Field-Programmable Logic and ... , 2000 - Springer

... **bus** is divided in two sections with **tri-state** drivers. ... to carry out vector multiplications without using any **bus** resources ... Table 1 . Board physical **statistics** ...

[Cited by 3](#) - [Web Search](#) - [BL Direct](#)

**A method to derive applicationspecific embedded processing cores - group of 8 »**

O Hebert, IC Kraljic, Y Savaria - Proc. of the 8th Int'l Symp. on Hardware/Software Codesign, 2000 - doi.ieeecomputersociety.org

... The **statistics** described earlier can lead to a number of ... a MAC unit to the destination **bus** of the ... conditions, one of which being a **tri-state bus** driver always ...

[Cited by 6](#) - [Web Search](#)

**Time frame generator for X-ray detectors and data acquisition systems for synchrotron radiation ...**

JB Khazaie, C Boulin - Nuclear Science, IEEE Transactions on, 1996 - ieeexplore.ieee.org

... several times and accumulate the results to get enough **statistics**. ... Proper isolation of the two **bus** structures using **tri-state** buffers allows the ...

[Cited by 1](#) - [Web Search](#) - [BL Direct](#)

**MBA, December 1980**

S CLEARANCES - 1998 - bus.umich.edu

... Age in Pension Plans," presented at the Bureau of Labor **Statistics**, Oct. ... Investment Advice," presented to the annual meeting of the **Tri-State** Academy of ...

[View as HTML](#) - [Web Search](#)

**Performance comparison of ILP machines with cycle time evaluation - group of 5 »**

T Hara, H Ando, C Nakanishi, M Nakaya - Proceedings of the 23rd annual international symposium on ... , 1996 - portal.acm.org

Page 1. Performance Comparison of ILP Machines with Cycle Time Evaluation

Tetsuya Hara, Hideki Ando, Chikako Nakanishi, Masao Nakaya ...

[Cited by 23](#) - [Web Search](#) - [BL Direct](#)

**Modeling design constraints and biasing in simulation using BDDs - group of 3 »**

J Yuan, K Shultz, C Pixley, H Miller, A Aziz - Proceedings of the 1999 IEEE/ACM international conference on ... , 1999 - portal.acm.org

... Table 2 reports the **statistics** of the designs. ... simulations X values were constantly generated on **tri-state** buses, indicating **bus** contentions, which ...

[Cited by 37](#) - [Web Search](#) - [BL Direct](#)